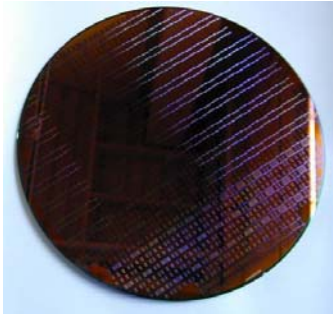
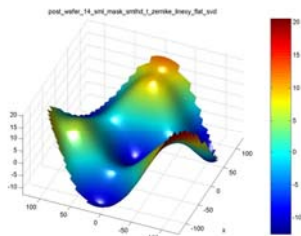


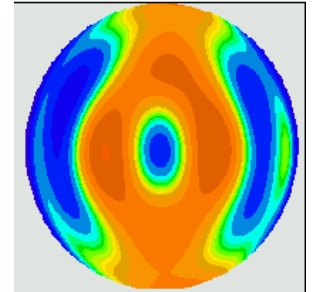
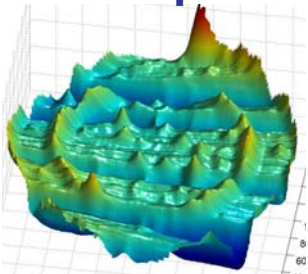
# MICRO DEVICE RELIABILITY FACILITY



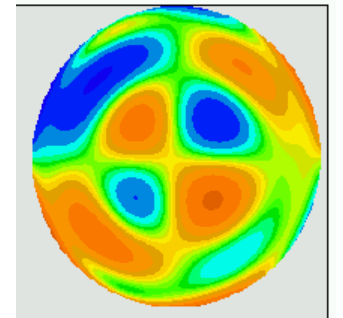
300 mm Wafer



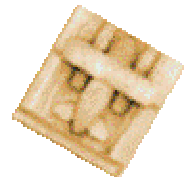
Shape



X Curvature,  
 $K_{11}$



Twist Curvature,  
 $K_{12}$



Measuring curvature and stresses in thin film structures deposited on wafers